Search Notes

Application/Control No.	Applicant(s)/Pater Reexamination	Applicant(s)/Patent under Reexamination	
09/242,772	VAN DE VEN ET	AL.	
Examiner	Art Unit		
Young J. Kim	1637		

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INTERFERENCE SEARCHED				
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Discussed Examiner Amendment and claim allowability with RQAS, Tony Caputa	3/8/2006	YJK
Discussed Examiner Amendment and claim allowability with TQAS, Yvonne Eyler	3/13/2006	YJK
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